

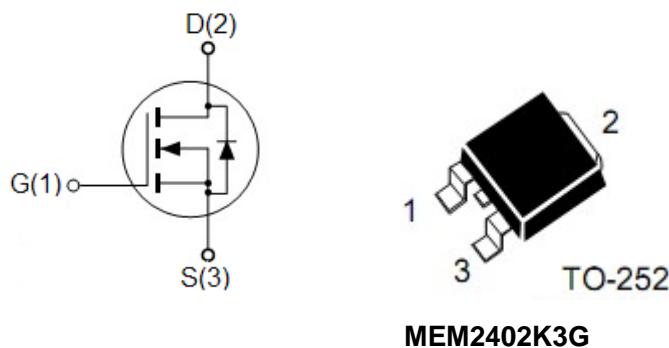


## N-CHANNEL Trench Power MOSFET MEM2402

### General Description

The MEM2402 combines advanced trench MOSFET technology with a low resistance package to provide extremely low RDS(ON). Those devices are suitable for use in PWM, load switching and general purpose applications.

### Pin Configuration



### Maximum Ratings( $T_a=25^\circ\text{C}$ )

Parameter		Symbol	Ratings	Unit
Drain-Source Voltage( $V_{GS}=0\text{V}$ )		$V_{DSS}$	60V	V
Gate-Source Voltage( $V_{DS}=0\text{V}$ )		$V_{GSS}$	$\pm 20$	V
Drain Current	$T_A=25^\circ\text{C}$	$I_D$	15	A
	$T_A=100^\circ\text{C}$		10.5	
Pulsed Drain Current (Note1)		$I_{DM}$	60	A
Total Power Dissipation	$T_A=25^\circ\text{C}$	$P_d$	23	W
Single Pulse Avalanche Energy (Note2)		$EAS$	25	mJ
Operating Temperature Range		$T_{Opr}$	-55-175	°C
Storage Temperature Range		$T_{stg}$	-55-175	°C

**Notes:** 1.Repetitive Rating :Pulse width limited by maximum junction temperature.

2.EAS condition  $T_{opr} = 25^\circ\text{C}$ ,  $V_{DD}=30\text{V}$ ,  $V_G=10\text{V}$ ,  $R_G=25\Omega$

### Features

- $V_{DS}=60\text{V}$ ,  $I_D=15\text{A}$
- $R_{DS(\text{ON})}<40\text{m}\Omega @ V_{GS}=10\text{V}$ (Typ:36 mΩ)
- Ultra Low On-Resistance
- PACKAGE : TO252

### Application

- Power switching application
- Load switching

### Thermal Characteristics

Parameter	Symbol	TYP.	MAX.	Unit
Thermal Resistance,Junction-to-Case	$R_{\theta JC}$	-	6.6	°C/W

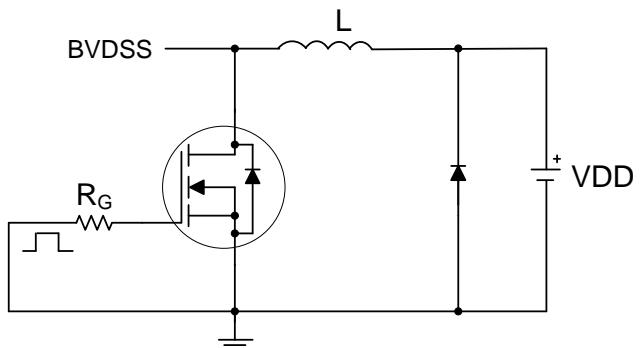
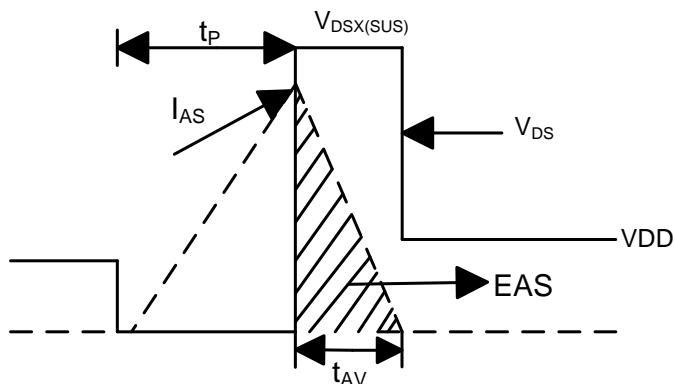
## Electrical Characteristics(T<sub>a</sub>=25°C)

Parameter	Symbol	Test Condition	Min	Type	Max	Unit
<b>Static Characteristics</b>						
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	60	-	-	V
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =250uA	1.0	2.2	3.0	V
Gate-Body Leakage	I <sub>GSS</sub>	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V	-	-	±100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =60V	T <sub>A</sub> =25°C	-	-	1 uA
		V <sub>GS</sub> =0V	T <sub>A</sub> =100°C	-	-	5 uA
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =12A	-	36	45	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =6A	-	37	50	mΩ
<b>Dynamic Characteristics</b>						
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =10V, I <sub>D</sub> = 15A	12	-	-	S
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V, f = 1 MHz	-	778	-	pF
Output Capacitance	C <sub>oss</sub>		-	66	-	
Reverse Transfer Capacitance	C <sub>rss</sub>		-	41	-	
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 15A	-	13.5	-	nC
Gate-Source Charge	Q <sub>gs</sub>		-	3.2	-	
Gate-Drain Charge	Q <sub>gd</sub>		-	6.2	-	
<b>Source-Drain Diode Characteristics</b>						
Source-Drain Current(Body Diode)	I <sub>SD</sub>		-	15	-	A
Pulsed Source-Drain Current(Body Diode)	I <sub>SD</sub>		-	60	-	A
Source-drain (diode forward) voltage(Note1)	V <sub>SD</sub>	T <sub>A</sub> =25°C, V <sub>GS</sub> =0V, I <sub>SD</sub> =1A	-	0.75	1.0	V
Reverse Recovery Time(Note1)	trr	T <sub>A</sub> =25°C, I <sub>F</sub> =15A, di/dt=100A/uA	-	27	-	nS
Reverse Recovery Charge(Note1)	Qrr		-	30	-	nC
Forward Turn-on Time	t <sub>on</sub>	Intrinsic turn-on time is negligible(turn-on) is dominated by L <sub>S</sub> +L <sub>D</sub>				
<b>Switching Characteristics</b>						
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DS</sub> = 30 V, R <sub>G</sub> = 3Ω V <sub>GS</sub> = 10V, R <sub>L</sub> = 2.5Ω	-	4.2	-	ns
Rise Time	t <sub>r</sub>		-	3.4	-	
Turn-Off Delay Time	t <sub>d(off)</sub>		-	16	-	
Fall-Time	t <sub>f</sub>		-	2	-	

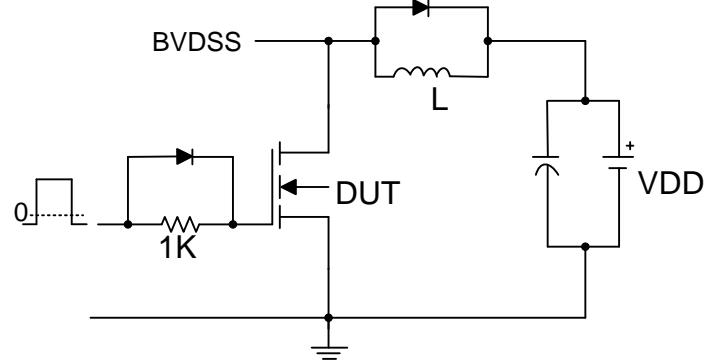
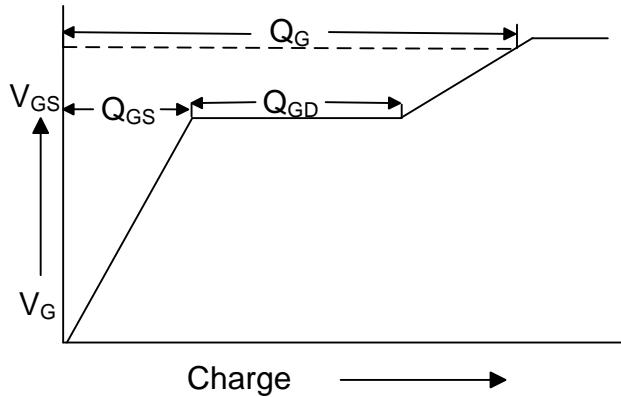
Notes 1. Pulse Test width≤300uS,Duty Cycle ≤1.5%,Starting T<sub>A</sub>=25°C

## Test Circuit

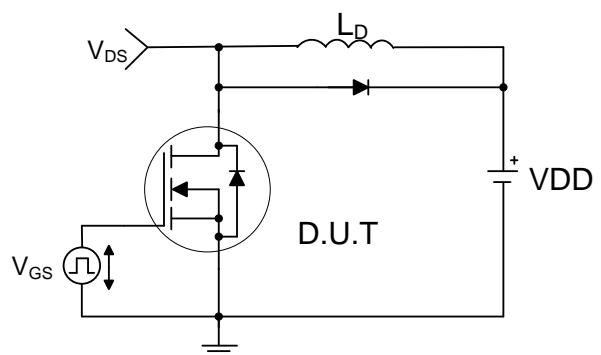
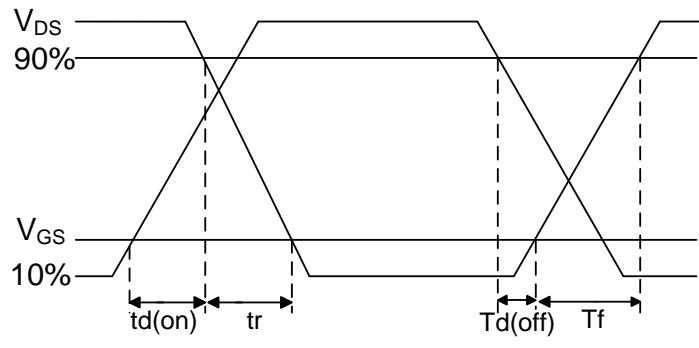
### 1. EAS Test Circuits



### 2. Gate Charge Test Circuits

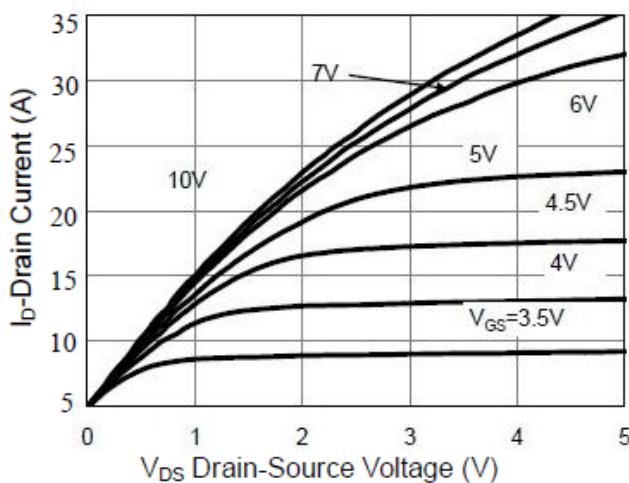


### 3. Switch Time Test Circuits

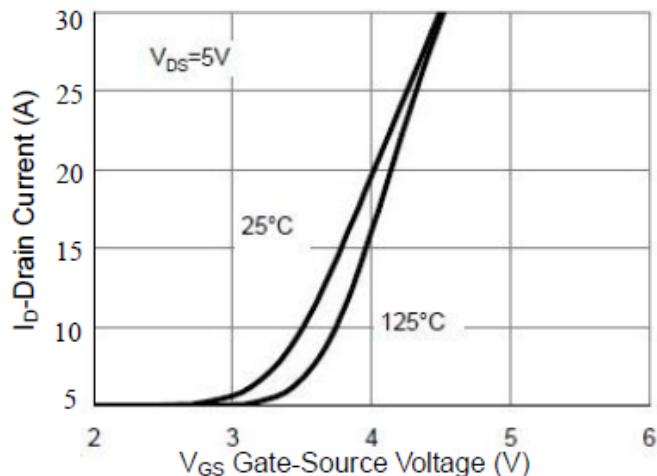


## Typical performance characteristics

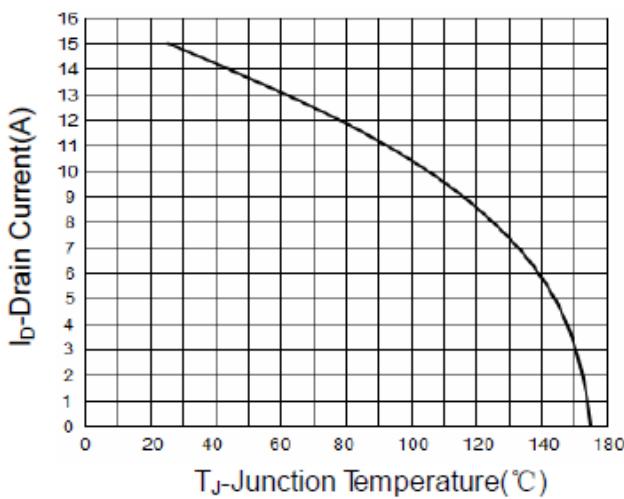
**Figure1. On-Region Characteristics**



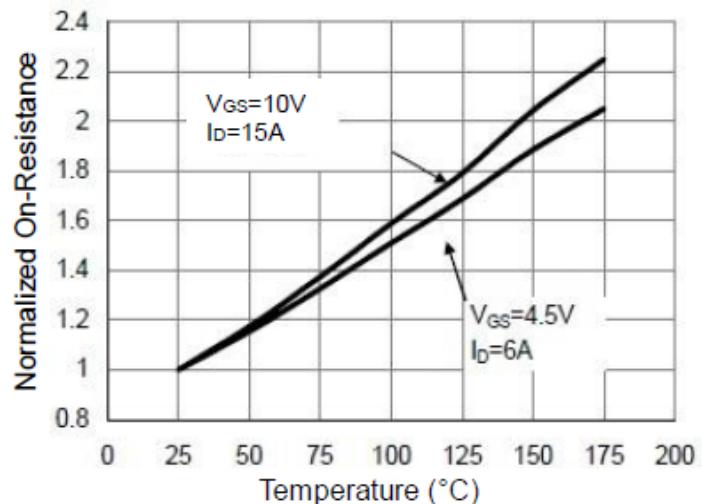
**Figure 2: Transfer Characteristics**



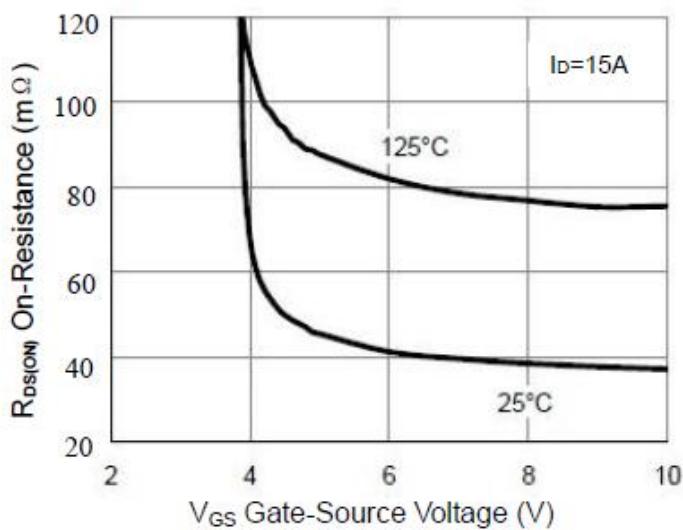
**Figure3. ID vs Junction Temperature**



**Figure4. On-Resistance vs. Junction Temperature**



**Figure5. On-Resistance vs. Gate-Source Voltage**



**Figure6. Body-Diode Characteristics**

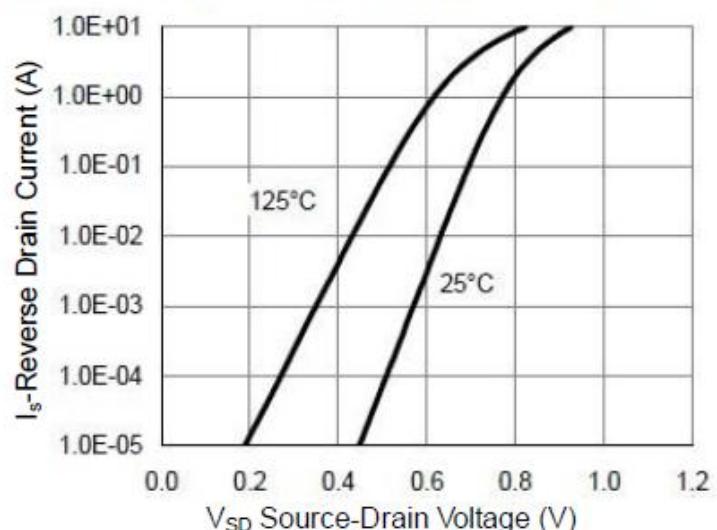


Figure7. Gate-Charge Characteristics

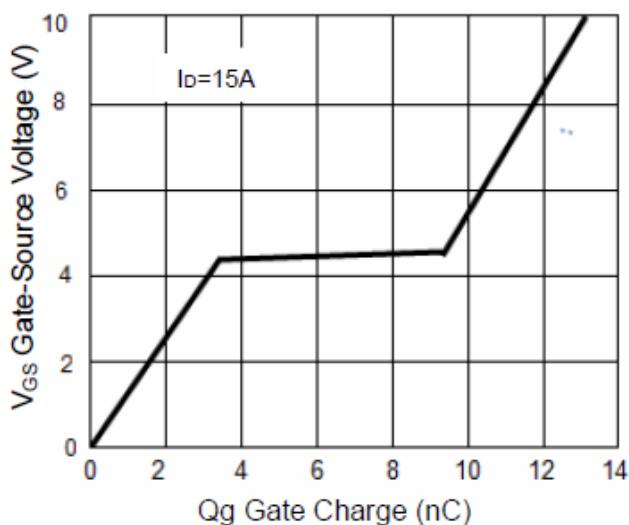


Figure 8. Capacitance Characteristics

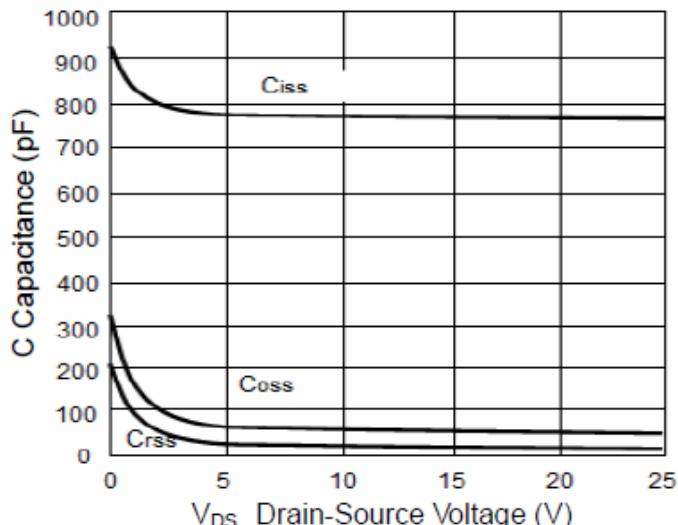


Figure 9. Maximum Forward Biased Safe Operating Area

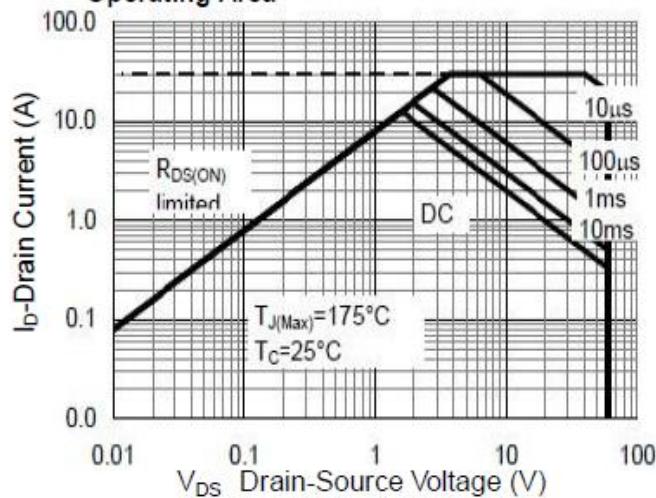


Figure10. Single Pulse Power Rating Junction-to-Case

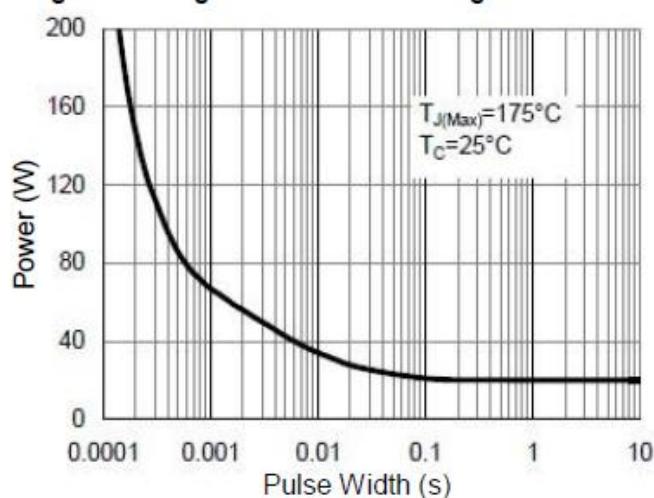
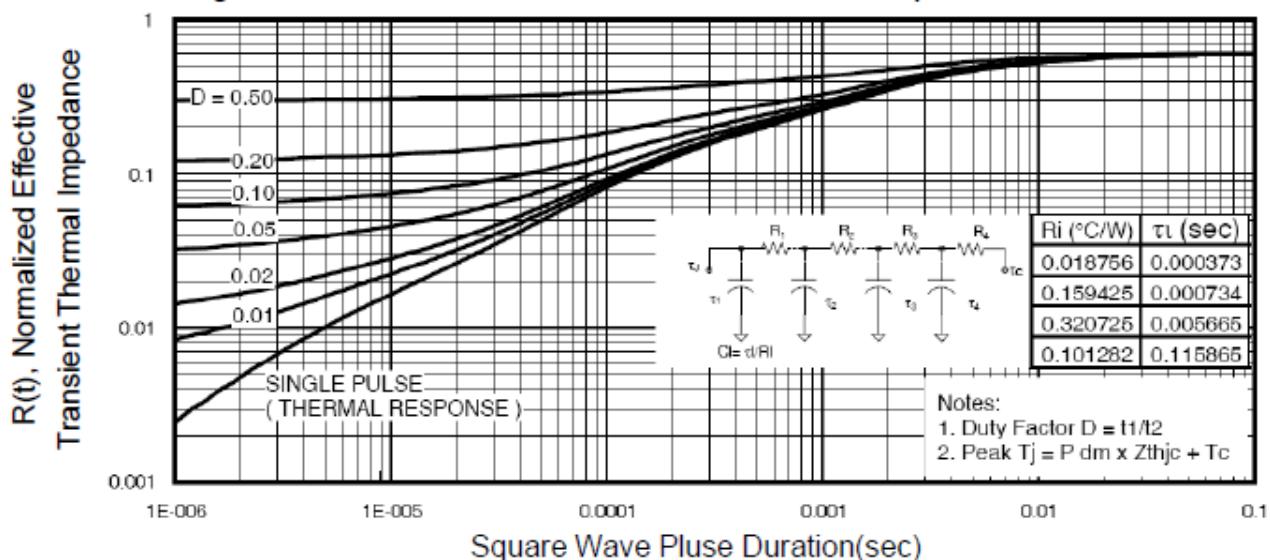
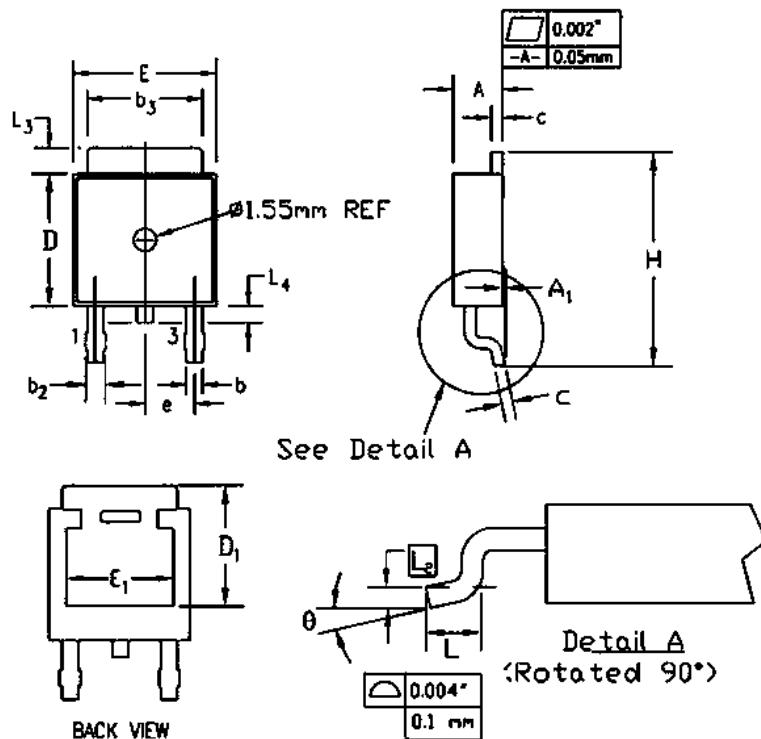


Figure11. Normalized Maximum Transient Thermal Impedance



## Package Information

Package Type: TO-252



DIM	Millimeters		Inches	
	Min	Max	Min	Max
A	2.19	2.38	0.086	0.094
A1	-	0.13	-	0.005
b	0.64	0.89	0.025	0.035
b2	0.84	1.14	0.033	0.045
b3	5.21	5.46	0.205	0.215
c	0.46	0.61	0.018	0.024
D	5.97	6.22	0.235	0.250
D1	5.21	-	0.205	-
E	6.35	6.73	0.250	0.265
E1	4.83	-	0.190	-
e	2.29REF		0.090REF	
H	9.65	10.41	0.380	0.410
L	1.40	1.78	0.055	0.070
L2	0.51REF		0.020REF	
L3	0.89	1.27	0.035	0.050
L4	0.64	1.01	0.025	0.040
$\theta$	$0^\circ$	$8^\circ$	$0^\circ$	$8^\circ$

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